

Search Notes



Application/Control No.

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Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	147	5-15-06	RLJ
327	156	5-15-06	RLJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
limited text search (see notes)	5-16-06	RLJ
text search (see notes)	5-16-06	RLJ
text search (see notes)	5-17-06	RLJ
text search (see notes)	5-17-06	RLJ